



DOCUMENT CHANGE REQUEST

DCR number 1288 Changes required for: Qualification
Date: 2020/06/18 Date sent: 2019/07/19
Status: IMPLEMENTED

Originator: Steve Thacker
Organisation: ESCC Executive Secretariat

Title: Transistors, Low Power, Complementary NPN/PNP Based on type 2ST3360

Number: 5207/009 Issue: 2

Other documents affected:

Page:

17

Paragraph:

Appendix A

Original wording:

See 5207/009 issue 2

Proposed wording:

Add new deviation to Para. 2.4.1, Room Temperature Electrical Measurements as follows:

DESCRIPTION OF DEVIATIONS

All AC characteristics (ref. Para. 2.4.3, Note 2) may be considered guaranteed but not tested if successful pilot lot testing has been performed on the wafer lot which includes AC characteristic measurements per the Detail Specification. A summary of the pilot lot testing shall be provided if required by the Purchase Order.

Justification:

This DCR is raised on behalf of Manufacturer: ST/F.

This DCR adds a deviation that is the same as used in other ESCC specs e.g. 5202/014, 5203/010, etc.

As confirmed by ST:

Based on our background on this device on parts already tested for QML system, we had 0 failure for AC parameters so far and very good statistics on both NPN & PNP sides (see attached file as an example)

Attachments:

d15_m19500773_sga4_dynamic_par.pdf

Modifications:

N/A

Approval signature:

A handwritten signature in black ink, appearing to read "Stephen R. ...".

Date signed:

2020-06-18